We Claim:

1. A method for trimming interface devices, which comprises:

providing a semiconductor device having a plurality of interface devices and providing each one of the plurality of interface devices with a settable control element;

providing a test apparatus having a current source;

connecting the current source in the test apparatus to an interface connection on the semiconductor device, the interface connection being connected to one of the plurality of interface devices;

controlling a measurement current produced by the current source and setting the control element of the one of the plurality of interface devices to an initial value;

providing a trimming unit in the semiconductor device;

using the trimming unit to acquire a measurement voltage produced by the measurement current in the one of the plurality of interface devices;

using the trimming unit to compare the measurement voltage with a nominal voltage;

based on a difference between the measurement voltage and the nominal voltage, setting the control element of the one of the plurality of interface devices to a trimming value at which the measurement voltage matches the nominal voltage; and

acquiring the trimming value for the control element of the one of the plurality of interface devices.

2. The method according to claim 1, which further comprises: storing the trimming value for the control element of the one of the plurality of interface devices in the semiconductor device in a nonvolatile manner.

3. The method according to claim 2, which further comprises: when the semiconductor device is started up, reading the trimming value stored in the semiconductor device into a trimming register controlling the control element of the one of the plurality of interface devices.

4. The method according to claim 2, which further comprises: during trimming, setting the control element of the one of the plurality of interface devices by setting a trimming register with the trimming unit.

5. The method according to claim 2, which further comprises:

transmitting a result obtained from comparing the measurement voltage and the nominal voltage to the test apparatus via a monitor output; and

during trimming, setting the control element of the one of the plurality of interface devices by writing, from the test apparatus, to a trimming register.

6. The method according to claim 2, which further comprises: transmitting the trimming value for the control element of the one of the plurality of interface devices to the test apparatus and impressing the trimming value onto the control element of the one of the plurality of interface devices in a nonvolatile manner using the test apparatus or a further programming apparatus.

7. The method according to claim 2, which further comprises: using the trimming unit to impress the trimming value for the control element of the one of the plurality of interface devices into a loading register in a trimming register.

8. The method according to claim 1 which further comprises: starting from an initial value, unidirectionally setting the control element of the one of the plurality of interface devices in stages until the trimming unit records a change of

an arithmetic sign for a difference between the measurement voltage and the nominal voltage.

9. The method according to claim 1, which further comprises:

providing the semiconductor device in a wafer; and

producing a plurality of interface connections for the semiconductor device as contact areas configured on a surface of the wafer.

10. The method according to claim 9, which further comprises: connecting the test apparatus to the semiconductor device by pressing a plurality of contact needles onto the contact areas.

11. The method according to claim 1, which further comprises: providing the semiconductor device as a DRAM having a DDRII interface.

12. The method according to claim 1, which further comprises: providing each one of the plurality of interface devices as a device selected from a group consisting of an output driver interface and a termination.

13. The method according to claim 1, which further comprises: providing the current source as an output driver operated in a current-limited manner for driving digital signals.

14. A semiconductor device comprising:

at least one interface device having a settable control element;

a trimming register connected to said control element; and

a trimming unit for writing to said trimming register based on a measured variable detected on said interface device;

said trimming unit connected to said interface device and said trimming register.

15. The semiconductor device according to claim 14, further comprising:

a monitor output for transmitting a value for said control element to a test apparatus;

said value being a measured variable and/or a trimming value; and said value being ascertained by said trimming unit.

16. The semiconductor device according to claim 14, wherein said trimming unit includes a reference voltage device and a voltage divider for producing a nominal voltage.

17. The semiconductor device according to claim 14, wherein:

said trimming unit has a comparator unit for providing an output signal obtained by comparing a nominal voltage with a measurement voltage produced in said interface device; and

said trimming unit has a logic unit for writing to said trimming register based on said output signal from said comparator unit.

18. The semiconductor device according to claim 14, wherein: said trimming unit has a nonvolatile memory unit being programmed based on a trimming value.

19. The semiconductor device according to claim 18, wherein: said memory unit is configured for directly controlling said control element.

20. The semiconductor device according to claim 18, wherein: said memory unit is configured for loading said trimming register.